

Dallas Semiconductor Reliability Report:

DS1921L-F52

lbutton

Summary Data with Chi-Square Distribution Assumed.
 Stress Ambient Temperature and Voltage to
 Field Ambient Temperature And Voltage
 Failure Rate Determined by Sum of Parts

Cf:
 Ea:
 β:

Tuse:
 Vuse:

QUALIFICATION VEHICLES INCLUDED IN THIS ANALYSIS:

<u>PRODUCT</u>	<u>REV</u>	<u>PIN COUNT</u>	<u>PACKAGE</u>	<u>SIZE</u>
BR1225	na	2	CELL	12
CRYSTAL	na	2	BARREL	
DS1921	A3	8	PDIP	300

STRESS	CONDITION	READPOINT	QUANTITY	FAILS	DEVICE HRS
BR1225					
HIGH TEMP STORAGE LIFE	110C	5500 HOURS	100	1	87823700
DATE CODE RANGE:	9015 to 9015		TOTALS:	1	DEVICE HRS: 8.78E+07
					FITs: 23
CRYSTAL					
NA			100	0	00000000
DATE CODE RANGE:	0 to 0		TOTALS:	0	DEVICE HRS: 1.00E+08
					FITs: 9
DS1921					
HIGH VOLTAGE LIFE	125C, 6.0 VOLTS	48 HOURS	228	0	1406336
HIGH VOLTAGE LIFE	125C, 6.0 VOLTS	336 HOURS	228	0	8363999
HIGH VOLTAGE LIFE	125C, 6.0 VOLTS	1000 HOURS	226	2	19113012
DATE CODE RANGE:	9922 to 9922		TOTALS:	2	DEVICE HRS: 2.89E+07
					FITs: 108

STRESS	CONDITION	READPOINT	QUANTITY	FAILS	DEVICE HRS
		FAILURE RATE	MTBF (yrs):	815	TOTAL FITs: 140
FILE #	FAILURE MODE	FAILURE MECHANISM			
24233	BATTERY CURRENT	IN PROCESS. MAY NOT VERIFY			
BATT	LOW BATTERY	ELECTROLYTE CONSUMPTION (Ea = 1.0ev)			